Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/696,771	GUHA ET AL.	
Examiner	Art Unit	_
Binh X. Tran	1765	

	SEARCHED				
Class	Subclass	Date	Examiner		
216	17	3/30/2006	ВТ		
216	60	3/30/2006	вт		
438	715	3/30/06	ВТ		
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INTERFERENCE SEARCHED				
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	DATE	EXMR
Search keywords and inventor's name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	3/30/2006	вт